

P19826.A02



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants : Noriaki YUKAWA et al.  
Group Art Unit 2625  
Appln. No : 09/629,141  
Examiner: S. Chawan  
Filed : July 31, 2000  
For : METHOD OF ERASING REPEATED PATTERNS AND  
PATTERN DEFECT INSPECTION DEVICE

**AMENDMENT UNDER 37 C.F.R. 1.116**

**RECEIVED**

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Sir :

In response to the Official Action of January 15, 2004, in which a three-month shortened statutory period for response was set to expire on April 15, 2004, and for which a three month extension of time is being filed to extend the period for response until July 15, 2004, applicants respectfully request reconsideration and withdrawal of the outstanding rejections set forth in the above-mentioned Official Action in view of the following amendments and remarks.

**Amendments to the claims** begin on page 2 of this Reply.

**Remarks** begin on page 5 of this Reply.